

SPM2864C_{25/30}

NMOS 64K-BIT ELECTRICALLY ERASABLE PROM

- Access Time 250ns/300ns
- 8,192 Words × 8 Bits
- Single 5V Supply

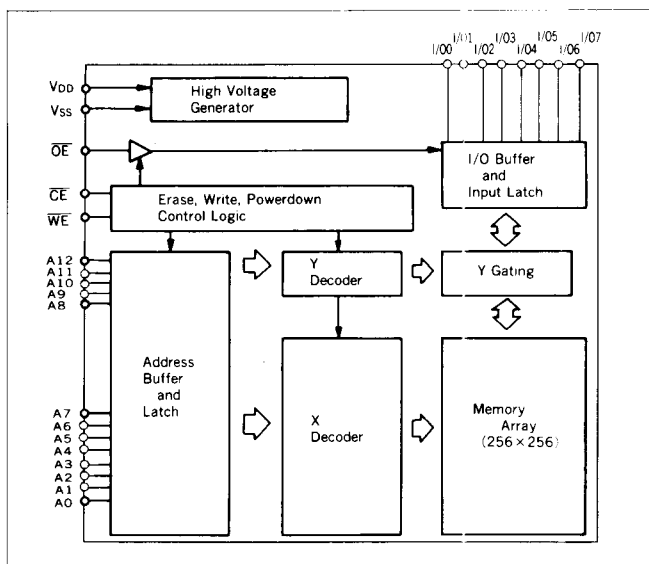
DESCRIPTION

The SPM2864C_{25/30} is an 8,192 words × 8bits electrically erasable programmable read-only memory (E²PROM). The SPM2864C_{25/30} can be easily erased and reprogrammed on a byte basis with a TTL-low level signal on \overline{WE} . The SPM2864C_{25/30} operates from a single 5V supply. External programming voltage and write pulse shaping are not required because they are generated by on-chip circuitry.

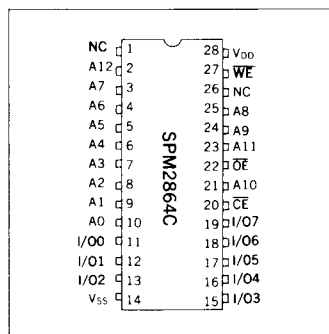
FEATURES

- Fast access time SPM2864C₂₅ 250ns (Max)
SPM2864C₃₀ 300ns (Max)
- Low supply current Standby : 40mA (Max)
Operation : 100mA (Max)
- Single power supply 5V ± 10%
- Address, Data, \overline{CE} , \overline{OE} Latches
- Byte erase / Byte write time 10ms (Typ)
- Chip erase time 20ms (Typ)
- Conforms to JEDEC byte-wide standard
- Reliable N-channel NMOS technology
- 10,000 erase/write cycles
- Package 28-pin DIP (plastic)

BLOCK DIAGRAM



PIN CONFIGURATION



PIN DESCRIPTION

A0 to A12	Address Input
\overline{CE}	Chip Enable
\overline{OE}	Output Enable
\overline{WE}	Write Enable
I/O0 to I/O7	Data I/O
V _{DD}	Power Supply (5V)
V _{SS}	Power Supply (0V)
NC	No connection

■ ABSOLUTE MAXIMUM RATINGS

($V_{SS}=0V$)

Parameter	Symbol	Ratings	Unit
Supply voltage*	V_{DD}	-0.6 to 7.0	V
Input voltage*	V_I	-0.6 to 7.0	V
Operating temperature	T_{opr}	0 to 70	°C
Storage temperature	T_{stg}	-55 to 125	°C

* With respect to V_{SS}

■ RECOMMENDED OPERATING CONDITIONS

($V_{SS}=0V$)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Supply voltage	V_{DD}		4.5	5.0	5.5	V
	V_{SS}		—	0	—	V
Input voltage	V_{IH}		2.0	—	$V_{DD}+1$	V
	V_{IL}		-0.1	—	0.8	V

■ ELECTRICAL CHARACTERISTICS

● DC Electrical Characteristics

($V_{DD}=5V \pm 10\%$, $V_{SS}=0V$, $T_a=0$ to $70^\circ C$)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
High level input voltage	V_{IH}		2.0	—	$V_{DD}+1$	V
Low level input voltage	V_{IL}		-0.1	—	0.8	V
Input leakage current	I_{LI}	$V_{DD}=5.5V$, $V_I=5.5V$	—	—	10	μA
Standby supply current	I_{DDs}	$\overline{CE}=V_{IH}$	—	—	40	mA
Operating supply current	I_{DDO}	$\overline{CE}=V_{IL}$	—	—	100	mA
Output leakage current	I_{LO}	$V_{DD}=5.5V$, $V_O=5.5V, 0.4V$	—	—	10	μA
High level output voltage	V_{OH}	$I_{OH}=-400\mu A$	2.4	—	—	V
Low level output voltage	V_{OL}	$I_{OL}=2.1mA$	—	—	0.4	V

● Terminal Capacitance

($f=1.0MHz$, $T_a=25^\circ C$)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Input capacitance	C_I	$V_I=0V$	—	—	6	pF
Output capacitance	C_O	$V_O=0V$	—	—	12	pF

Read Mode

●AC Electrical Characteristics

($V_{DD} = 5V \pm 10\%$, $V_{SS} = 0V$, $T_a = 0$ to $70^\circ C$)

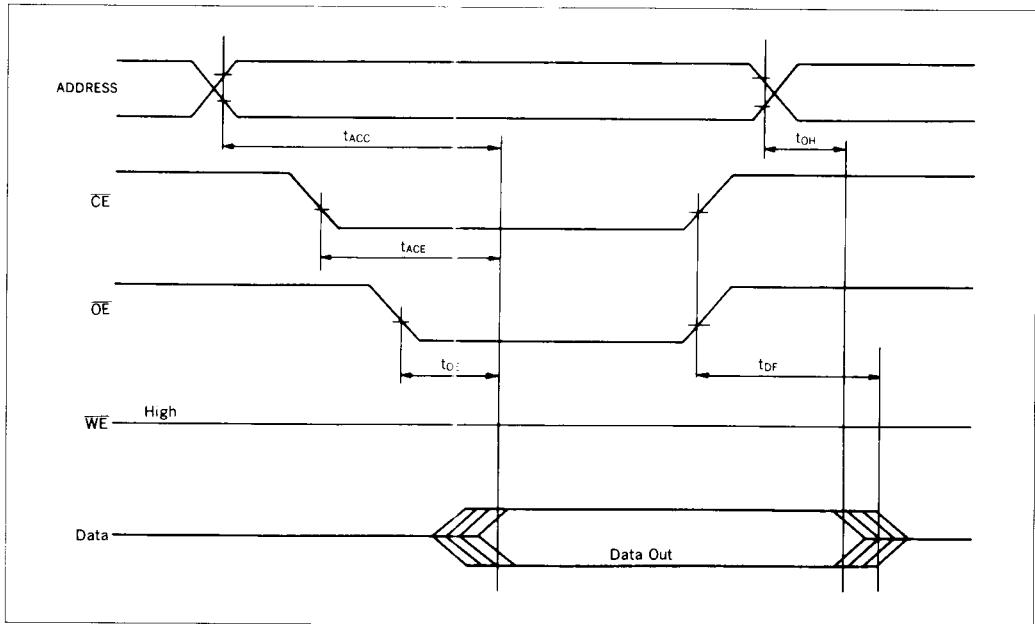
Parameter	Symbol	Conditions	SPM2864C ₂₅		SPM2864C ₃₀		Unit
			Min	Max	Min	Max	
Address access time	t_{ACC}	$WE = V_{IH}$	—	250	—	300	ns
Chip enable access time	t_{ACE}	$WE = V_{IH}$	—	250	—	300	ns
Output enable access time	t_{OE}	$WE = V_{IH}$	—	100	—	150	ns
Output floating	t_{DF}^{*2}	$WE = V_{IH}$	0	90	0	130	ns
Output hold time	t_{OH}	$WE = V_{IH}$	0	—	0	—	ns

* 1 Input pulse levels 0.4V to 2.4V, Input rise and fall times ≤ 20 ns, Output load 1 TTL + 100pF

Reference level for measuring timing 0.8V and 2.0V

* 2 t_{DF} defines the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.

●Timing Chart



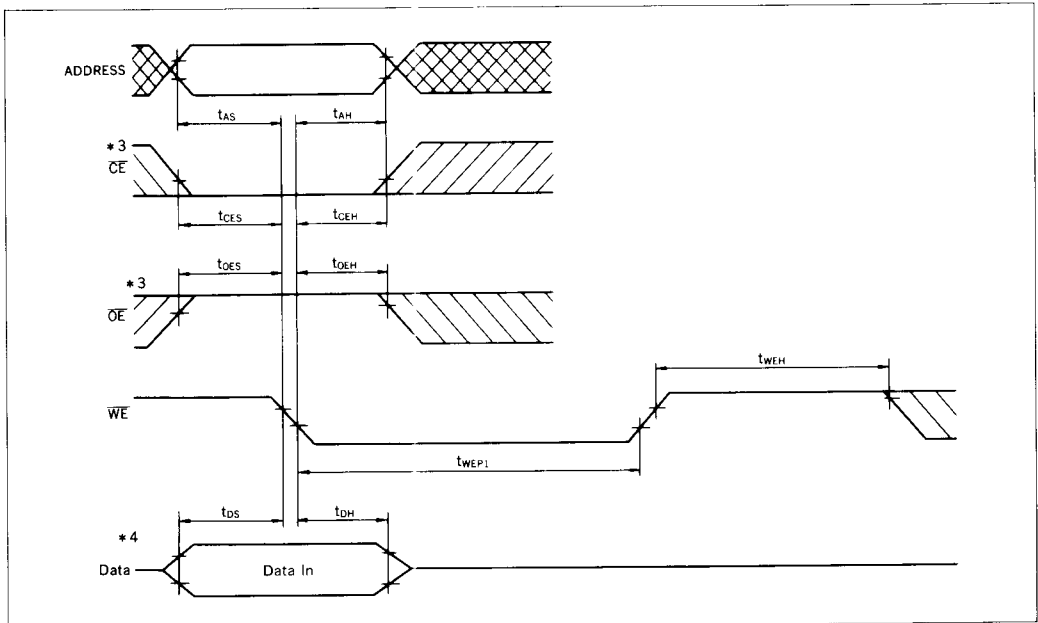
Byte Erase and Byte Write Mode

● AC Electrical Characteristics

($V_{DD}=5V \pm 10\%$, $V_{SS}=0V$, $T_a = 0$ to $70^\circ C$)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Address setup time	t_{AS}	Input pulse levels: 0.4V to 2.4V Input rise and fall times: $\leq 20ns$ Output load: 1 TTL + 100pF Reference level for measuring timing: 0.8V and 2.0V	0	—	—	ns
Chip enable setup time	t_{CES}		0	—	—	ns
Output enable setup time	t_{OES}		0	—	—	ns
Data setup time	t_{DS}		0	—	—	ns
Address hold time	t_{AH}		100	—	—	ns
Data hold time	t_{DH}		100	—	—	ns
Chip enable hold time	t_{CEH}		100	—	—	ns
Output enable hold time	t_{OEH}		100	—	—	ns
WE pulse width	t_{WEP1}		8	—	15	ms
WE high time	t_{WEH}		1,000	—	—	ns

● Timing Chart



*3 \overline{CE} or \overline{OE} should be "1" and in Standby Mode or Deselect Mode before Write/Erase operation.

*4 I/O0 to I/O7 must be "1" in Byte Erase.

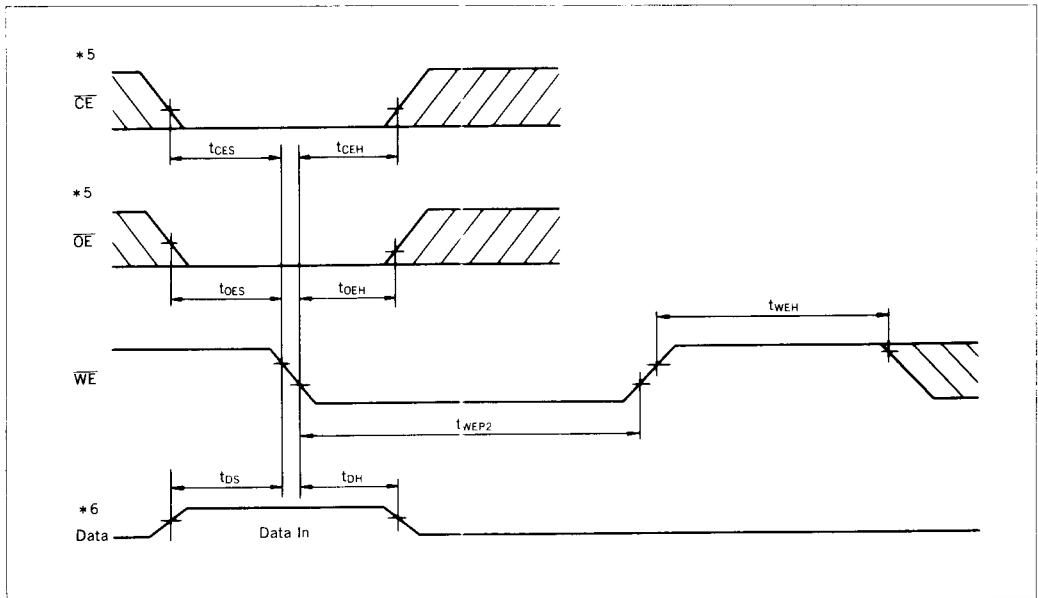
Chip Erase Mode I

● AC Electrical Characteristics

($V_{DD} = 5V \pm 10\%$, $V_{SS} = 0V$, $T_a = 0$ to $70^\circ C$)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Chip enable setup time	t_{CES}	Input pulse levels: 0.4V to 2.4V Input rise and fall times: $\leq 20ns$ Output load: 1 TTL+100pF Reference level for measuring timing: 0.8V and 2.0V	0	—	—	ns
Output enable setup time	t_{OES}		0	—	50	ns
Data setup time	t_{DS}		0	—	—	ns
Data hold time	t_{DH}		100	—	—	ns
Chip enable hold time	t_{CEH}		100	—	—	ns
Output enable hold time	t_{OEH}		100	—	—	ns
WE pulse width	t_{WEP2}		15	—	25	ms
WE high time	t_{WEH}	1,000	—	—	ns	

● Timing Chart



*5 \overline{CE} or \overline{OE} should be "1" and in Standby Mode or Deselect Mode before Chip Erase operation.

*6 I/O0 to I/O7 must be "1" in Chip Erase operation.

"H" or "L" about Address.

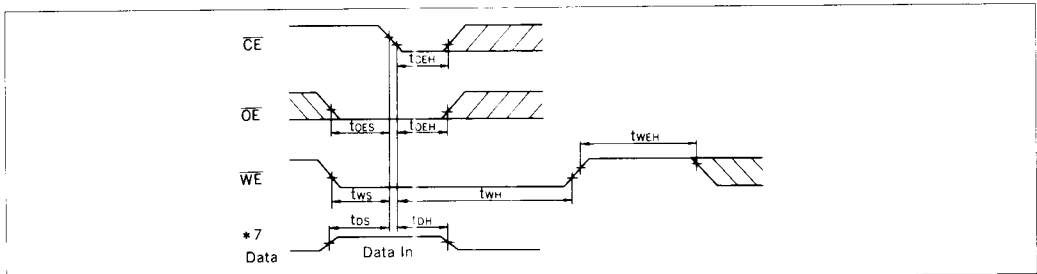
Chip Erase Mode II

● AC Electrical Characteristics

($V_{DD}=5V \pm 10\%$, $V_{SS}=0V$, $T_a=0$ to $70^\circ C$)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Output enable setup time	t_{OES}	Input pulse levels: 0.4V to 2.4V Input rise and fall times: ≤ 20 ns	0	—	—	ns
WE setup time	t_{WS}		0	—	—	ns
Data setup time	t_{DS}	Output load: 1 TTL + 100pF	0	—	—	ns
Data hold time	t_{DH}		100	—	—	ns
Chip enable hold time	t_{CEH}	Reference level for measuring timing: 0.8V and 2.0V	100	—	—	ns
Output enable hold time	t_{OEH}		100	—	—	ns
WE pulse width	t_{WH}		15	20	25	ms
WE high time	t_{WEH}		1,000	—	—	ns

● Timing Chart



*7 I/O1 to 7 must be "1" in Chip Erase Operation.
"H" or "L" about Address.

■ FUNCTIONS

● Truth Table

Pin name / Mode	Data I/O I/O0 to I/O7	\overline{CE}	\overline{OE}	WE
Read	Output data	L	L	H
Standby	Hi-Z	H	X	X
Byte Erase	$D_{IN}=H$	L	H	L
Byte Write	Input data	L	H	L
Chip Erase	$D_{IN}=H$	L	L	L
Deselect	Hi-Z	L	H	H

X: "H" or "L"

■ PACKAGE DIMENSIONS

